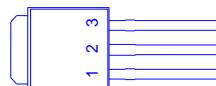
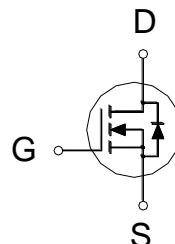


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P0460EI
TO-251
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
600V	2.3Ω	4A


1. GATE
2. DRAIN
3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	4	A
		2.5	
Pulsed Drain Current ^{1, 2}	I_{DM}	20	A
Avalanche Current ³	I_{AS}	4	
Avalanche Energy ³	E_{AS}	80	mJ
Power Dissipation	P_D	62.5	W
		25	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed³ $V_{DD} = 50\text{V}$, $L = 10\text{mH}$, starting $T_J = 25^\circ\text{C}$ **ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	600			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	2	3.2	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 30\text{V}$			± 100	nA
Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 25^\circ\text{C}$			1	μA
		$V_{DS} = 480\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 100^\circ\text{C}$			10	

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Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 2A		1.85	2.3	Ω
Forward Transconductance ¹	g _f	V _{DS} = 15V, I _D = 2A		5.8		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		517		pF
Output Capacitance	C _{oss}			62		
Reverse Transfer Capacitance	C _{rss}			11		
Total Gate Charge ²	Q _g	V _{DD} = 480V, I _D = 4A, V _{GS} = 10V		18		nC
Gate-Source Charge ²	Q _{gs}			2.8		
Gate-Drain Charge ²	Q _{gd}			8.3		
Turn-On Delay Time ²	t _{d(on)}	V _{GS} = 10V , V _{DD} = 300V, I _D = 4A, R _G = 25Ω		18		nS
Rise Time ²	t _r			46		
Turn-Off Delay Time ²	t _{d(off)}			46		
Fall Time ²	t _f			50		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current ³	I _S				4	A
Forward Voltage ¹	V _{SD}	I _F = 4A, V _{GS} = 0V			1.5	V
Reverse Recovery Time	t _{rr}	I _F = 4A, dI _F /dt = 100A / μS		383		nS
Reverse Recovery Charge	Q _{rr}			2.2		uC

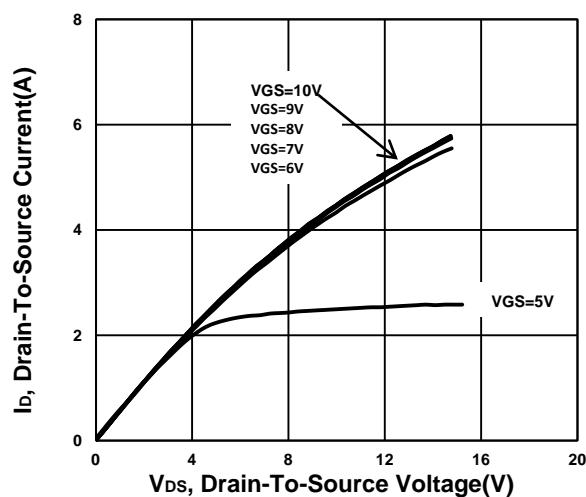
¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

NIKO-SEM

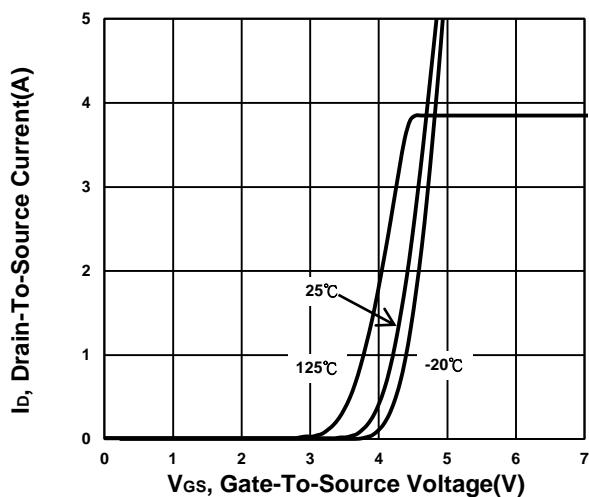
**N-Channel Enhancement Mode
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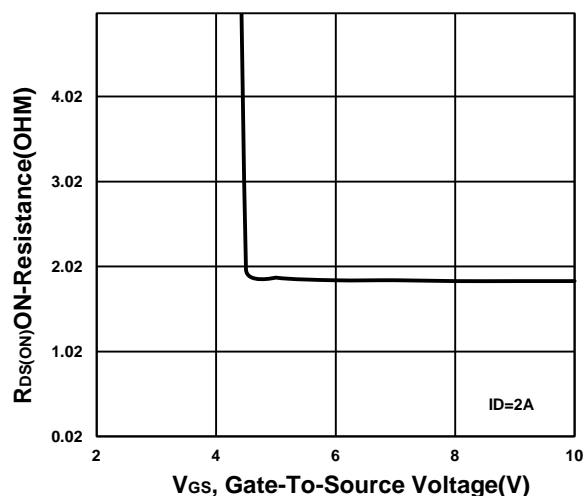
Output Characteristics



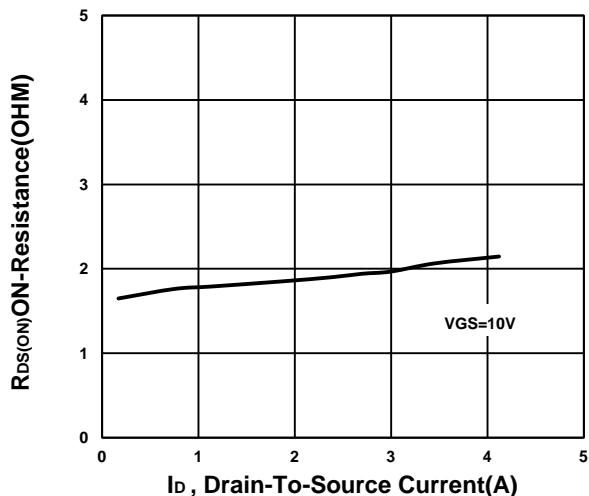
Transfer Characteristics



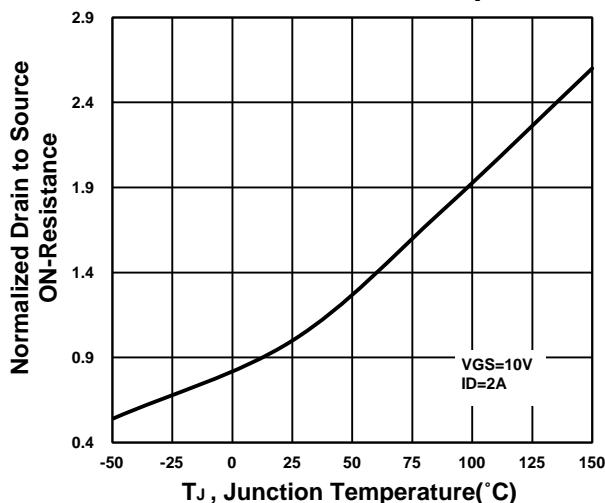
On-Resistance VS Gate-To-Source



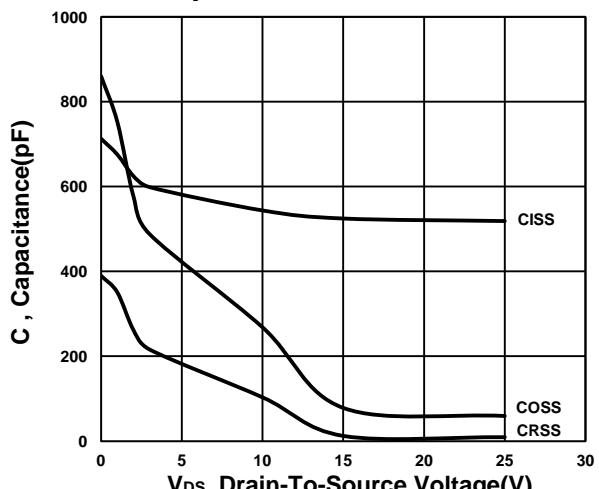
On-Resistance VS Drain Current

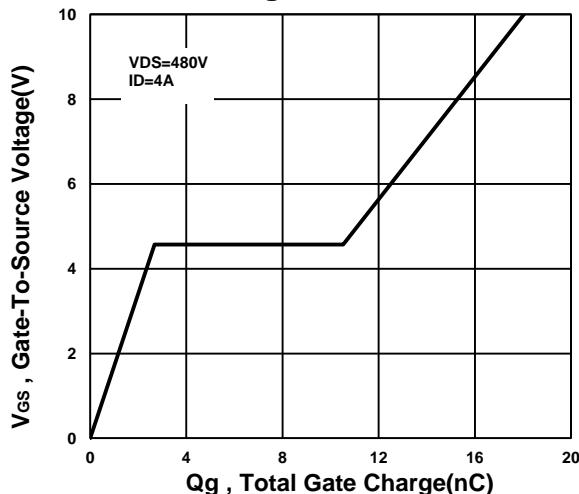
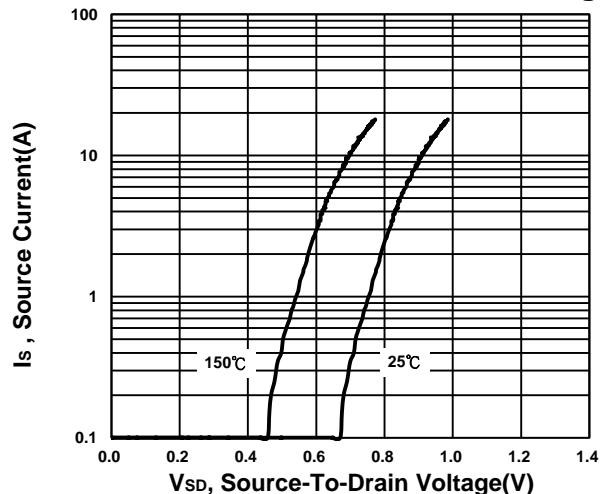
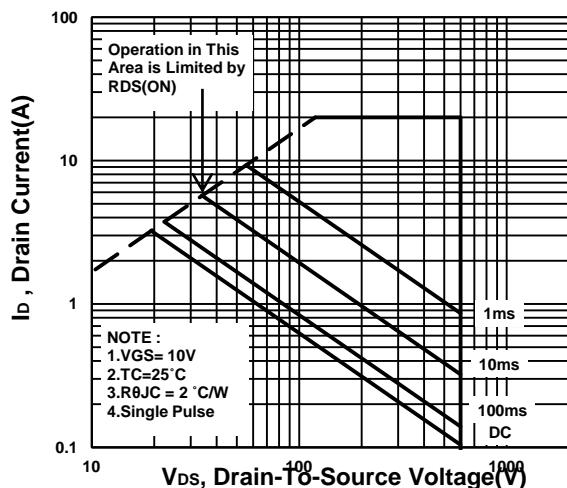
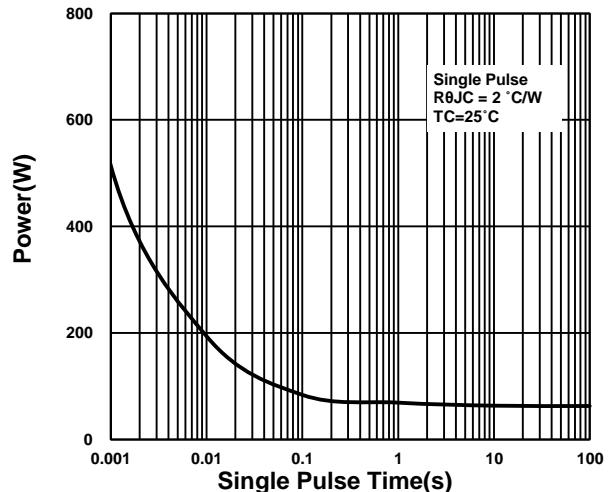


On-Resistance VS Temperature



Capacitance Characteristic



NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P0460EI
TO-251
Halogen-Free & Lead-Free****Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**